



November 2011 Newsletter

Joint Section Chapter – Boston – New Hampshire – Providence

September 2011 - October 2011

<http://www.ieee.org/bostonrel>

Dear Reliability Joint Section Chapter members,

As the holidays approach, I'd like to wish all of you happy holidays and a safe and joyful year end. I also wish to personally thank our 2011 Advisory Committee members who gave of their personal time and dedication to enable our chapter success. In 2012, I encourage you to consider volunteering with the chapter or join the AdCom. I'm certain you'll have a great time!

Sincerely,

Ramon De la Cruz
2011 Chapter Chair

In this Issue

Recent Activities

- September 14, 2011 • "Utilizing risk management to minimize cost, schedule and performance problems on your project," Liz Markewicz, Raytheon Company
- October 12, 2011 • "Enhanced Reliability through Automated Design Analysis Software for the Electronics Industry (Sherlock 2.0 Overview)," Gregg P. Kittlesen, Ph.D., DfR Solutions

Upcoming Events

- Nov 7 – Dec 9, 2011 • 2012 AdCom Officer Elections
- November 10, 2011 • "Failure Mode and Effects Analysis, Design & Process- Techniques, Tools," Angelo Scangas, Quality Support Group, Inc.
- December 14, 2011 • Joint Section Reliability Chapter Annual Past Chairs Dinner Meeting
• "Counterfeit Component Avoidance Workshop – CCAW," Don Trenholm, President, Custom Analytical Services, Inc.
- January 2012 • No meeting
- February 8, 2012 • Joint IEEE/NE-ESDA meeting, Andrew Kopanski, MIT Lincoln Lab

Society Participation

- <http://www.ieee.org/bostonrel>, [Join our E-Mail Distribution List](#)
- [Suggest a Meeting Topic](#), [Join Technology Development](#)
- [Join IEEE](#), [Join an IEEE Society](#), [IEEE Reliability Society Membership](#)

Recent Activities

September 2011:

On Wednesday, September 14th Liz Markewicz, Raytheon Company, presented “Utilizing risk management to minimize cost, schedule and performance problems on your project” at Teradyne, North Reading MA with 36 members and guests in attendance.

This presentation provided a systematic overview of the risk management process, including:

- Definition and planning of the risk process.
- How to assess the key elements of risk and use this as a means to prioritize deployment of scarce resources toward risk management.
- Tips on determining if your project has “the right” list of risks?



Liz Markewicz engaged the audience with a systematic approach to defining and managing project risks.



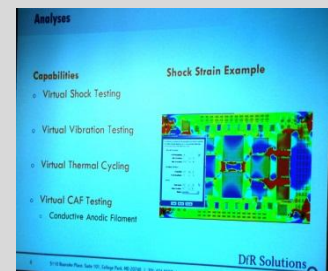
Liz Markewicz itemized the step-by-step approach to manage risk at Raytheon.

October 2011:

On Wednesday, October 12th Gregg P. Kittlesen, Ph.D., Sr. Member of Technical Staff, DfR Solutions presented, "Enhanced Reliability through Automated Design Analysis for the electronics Industry (Sherlock 2.0 Overview)" at Teradyne, North Reading MA to 27 members and guests.



Greg Kittlesen engaged the audience in an active discussion of the features of Sherlock 2.0 as he presented a tutorial from the software package. "Sherlock 2.0, developed by DfR Solutions, is automated design analysis software. The software tool is designed to enable electronics manufacturers to design product reliability earlier in the product development process, contributing to quicker time to market, reduced development costs, improved customer satisfaction, and higher profits. Use and results of automated design analysis software approach using Sherlock 2.0 for analyzing, grading, and certifying the expected reliability of products at the circuit card assembly level was presented."



Upcoming Meetings and Events

2012 AdCom Officer Elections:

The 2012 IEEE Reliability Joint Section Chapter (Boston - New Hampshire - Providence) Officer Elections opened for on-line voting on November 7 and will close on December 9.

For the 2012 term the candidates are:

- Chair: Daniel Weidman (MIT Lincoln Lab) or write-in
- Vice-chair: Ramon De la Cruz (Teradyne) or write-in
- Treasurer: Don Markuson (Hitachi Consulting) or write-in
- Secretary: Aaron DerMarderosian Jr. (Raytheon) or write-in

Election results will be announced at the December annual past chairs dinner meeting.

November 10, 2011:

On Thursday, November 10th Angelo Scangas, President, Quality Support Group, Inc. will present "Failure Mode and Effects Analysis, Design & Process - Techniques, Tools," at Teradyne in North Reading MA.

Failure Mode & Effects Analysis (FMEA) is a risk assessment tool designed to identify potential failure modes, determine the associated level of risk, and mitigate the risk to an acceptable level.

This presentation will provide an overview of the FMEA, including:

- How to determine the right time to initiate FMEA.
- How to identify and classify potential failure modes.
- How to build a cross-sectional team qualified to perform FMEA.
- The process of evaluating potential failure modes for severity and probability.
- How to prioritize for maximum effectiveness and assure maximum efficiency.

December 14, 2011:

On Wednesday, December 14, 2011 the Joint Section Reliability Chapter Annual Past Chairs Dinner and monthly meeting will be held with a presentation by Donald Trenholm, President, Custom Analytical Services, Inc., "Counterfeit Component Avoidance Workshop – CCAW" at Teradyne Inc. North Reading MA.

This presentation will give attendees visual access to fraudulently altered devices, including:

- Refurbished as well as cloned samples.
- Tips on distinct characteristics that give them away.
- The art of refurbishing these reclaimed devices.
- Primary sources of counterfeit components.

The audience will have improved ability to find these fraudulent devices at incoming inspection.

January 2012: No meeting.

February 8, 2012:

Joint IEEE/NE-ESDA meeting - Andrew Kopanski, MIT Lincoln Lab.

Society Participation

Please check our website periodically for updates on upcoming events! <http://www.ieee.org/bostonrel>

- If you would like to present a reliability based topic at a future meeting, have meeting topic suggestions, or ideas about how to improve our meetings, we want to hear from you! Please send an e-mail to any of the AdCom members, or go to our website and click on [Suggest a Meeting Topic](#).
- To participate or provide input to chapter technology development activities, sign up to become a TDC (Technology Development Committee) participant using our website by clicking on [Technology Development](#).
- You can also be added to the chapter e-notice distribution via our website by clicking on [Subscribe to E-Notices](#), or send a request to dermarderosiana@ieee.org (Vice-Chair, notices, and registration).

Acknowledgements:

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http://ewh.ieee.org/r1/boston/rl/newsletters/boston_chapter_newsletter_nov11.pdf